Abstracts

A Rigorous Technique for Measuring the Scattering Matrix of a Multiport Device with a Two-Port Network Analyzer (Comments)

H. Dropkin. "A Rigorous Technique for Measuring the Scattering Matrix of a Multiport Device with a Two-Port Network Analyzer (Comments)." 1983 Transactions on Microwave Theory and Techniques 31.1 (Jan. 1983 [T-MTT] (Joint Special Issue on Monolithic Microwave IC's)): 79-81.

The recent article by Tippet and Speciale uses the matrix formulation of the generalized scattering parameter renormalization transformation in the form.

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